Application/Control No. 10/075,456 Reexamination GEIER ET AL Examiner Audrey Y. Chang Applicant(s)/Patent Under Reexamination GEIER ET AL Page # of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name .	Classification
	Α	US-4,682,029	07-1987	Diepeveen et al	250/330
	В	US-5,557,454	09-1996	Takahashi	359/378
	С	US-5,588,948	12-1996	Takahashi et al	600/111
	D	US-5,748,367	05-1998	Lucke et al	359/385
	Ε	US-5,835,264	11-1998	Tandler et al	359/377
	F	US-6,348,994	02-2002	Geier et al	359/465
	G	US-			
	н	US-			
	_	US-			
	7	US-			
	К	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	R					
	s					
	T					

NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.